Effects of ZnO and Ce³⁺ incorporation on the photoluminescence and cathodoluminescence intensity of Pr³⁺ doped SiO₂.

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Abstract. The successful incorporation of ZnO nanoparticles and Ce^{3+} ions in Pr^{3+} doped SiO₂ using a sol-gel process is reported. SiO₂:Pr³⁺ gels, with or without ZnO and Ce³⁺, were dried at room temperature and annealed at 600 °C. The Field Emission Scanning Electron Microscopy indicated clustered SiO₂ nanoparticles with particle size diameter ranging from 20 to 120 nm while the energy dispersive x-ray spectroscopy (EDS) revealed the presence of Zn, Ce, and Pr clustures enveloped in the SiO₂ matrix. The emission intensity from SiO₂:Pr³⁺-Ce³⁺ at 494 nm was slightly enhanced compared to Ce³⁺ singly doped SiO₂. The red emission of Pr³⁺ was enhanced when ZnO nanoparticles were incorporated in SiO₂ suggesting that energy was transferred from ZnO to Pr³⁺. Possible energy transfer mechanisms between Pr³⁺ and Ce³⁺ and between ZnO and Pr³⁺ are discussed in detail.

1. Introduction

Among rare earths, trivalent praseodymium (Pr^{3+}) has been used as an activator in various host matrices to prepare phosphors [1-4] that can be used in different types of light emitting devices. The possibility of enhancing luminescence efficiency via energy transfer between activator ions (i.e. the sensitizer and the acceptor) was predicted by Dexter [5] in the 1960s. Studies of energy transfer process between Pr^{3+} and other ions co-doped in the same host matrix have been reported [6,7]. Interest has also been focused on nanocrystalline semiconducting quantum dots as they are considered as another good choice of sensitizing centres for radiative relaxation of activator ions since their excitation cross sections are very high due to the efficient band-to-band absorptions. Rare earth ions doped glass matrices containing nanocrystal semiconducting quantum dots prepared by the sol-gel

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method have been reported [8,9]. In such cases, the enhanced luminescence from rare earth ions can be achieved by efficient energy transfer from the quantum dots to rare earth ions. In the present work, we report the enhanced emission of Pr^{3+} induced by energy transfer from ZnO nanoparticles incorporated in situ in sol-gel silica under VUV and electron beam excitation. Energy transfer between Pr^{3+} -Ce³⁺ co-doped in SiO₂ was also studied under electron beam excitation.

2. Experimental

2.1. Preparation of $SiO_2:Ce^{3+}-Pr^{3+}$ and $ZnOSiO_2:Pr^{3+}$

 $SiO_2:Pr^{3+}$ co-doped with different concentrations of Ce³⁺ phosphor samples were prepared by mixing 0.05 mol of tetraethylorthosilicate (TEOS), 0.1 mol of H₂O, 0.1 mol of ethanol, and 0.145 mol of dilute nitric acid. The mixture was stirred at room temperature for 1 hour. The resulting transparent sol was mixed with a desired amount of Pr(NO)₃.6H₂O dissolved in 5 ml of ethanol and was stirred for 30 minutes. A desired amount of Ce(NO)₃.6H₂O dissolved in 5 ml of ethanol was also added to the solution and stirred further for 30 minutes until a gel formed. The gel was then dried at room temperature for 3-8 days. The dried gel was prepared by mixing the SiO₂:Pr³⁺ sol with ZnO nanoparticles suspended in ethanol. The detailed preparation of ZnO nanoparticles has been reported [8].

The particle morphology was analyzed by JEOL 2100 High Resolution Transmission Electron Microscopy (HRTEM) and JEOL JSM-7500F, Field Emission Scanning Electron Microscope (FESEM). The cathodoluminescence (CL) data of the phosphor samples were recorded using an Ocean Optics S2000 spectrometer coupled with an ultra high vacuum chamber of the Physical Electronics PHI 549 Auger electron spectrometer. The photoluminescence (PL) data was recorded at the Deutsche Elektronen Synchrotron (DESY) using the setup at SUPERLUMI experimental station of HASYLAB in Hamburg. The emission spectrum of ZnO was obtained using a LS 55, Fluorescence spectrometer.

3. Results and discussion

3.1. Particle morphology, size, and phase structure

The FE-SEM image in figures 1 illustrates the morphologies of the SiO₂ nanoparticles calcined at 600 $^{\circ}$ C for 2 hrs. The image exhibits the agglomeration of mostly spherical SiO₂ particles with an average particle size in the range of ~20 to 120 nm in diameter. Similar morphology was observed for ZnO.SiO₂:Pr³⁺ and SiO₂:Pr³⁺-Ce³⁺ samples. Figure 2 (a) and (b) show the XRD patterns of SiO₂ nanoparticles and ZnO nanoparticles, repsectively. The XRD patterns of the ZnO nanoparticles presented in figure 2 (b) are consistent with a hexagonal phase of ZnO referenced in JCPDS file No. 80-0075. The broadening of the ZnO diffraction peaks is attributed to the smaller particle sizes. The average crystallite size of the ZnO nanoparticles estimated using Scherer's equation was ~ 4 nm. Figure 2 (a) shows only one broad diffraction peak of amorphous SiO₂ at 22°. The diffraction peaks of SiO₂:Ce³⁺-Pr³⁺</sup> and ZnOSiO₂:Pr³⁺ samples resembled that of pure SiO₂ probably due to the relatively low concentration of Pr³⁺and the ZnO nanoparticles and/or high amorphous scattering background from the SiO₂ matrix [8]. The presence of the Pr³⁺,Ce³⁺ ions and ZnO nanoparticles in the phosphor powders (not shown) was confirmed by Electron Dispersive Spectroscopy (EDS).



Fig. 1 FE-SEM image of SiO₂.



Fig.2 XRD patterns of the (a) SiO_2 nanoparticles after calcination at 600 °C and (b) ZnO nanoparticles dried at 90 °C.

3.2. PL and CL properties of $ZnO.SiO_2$: Pr^{3+} .

CL spectra of the SiO₂, SiO₂:0.2 mol% Pr³⁺ and ZnO.SiO₂:0.2 mol% Pr³⁺ nanophosphor powders excited by 2 keV electrons, at 20 μ A beam current in a high vacuum chamber at a base pressure of ~ 1.6 x 10⁻⁸ Torr are shown in figure 3. The CL spectrum of SiO₂ showed the emission peak at 445 nm which can be assigned to structural defects in the SiO₂ network or charge transfer between O and Si atoms [8]. The characteristic emission peaks with maximum emission at 614 nm that can be associated with transitions in Pr³⁺ were observed from both SiO₂:Pr³⁺ and ZnO.SiO₂:Pr³⁺samples. This emission can be assigned to the transitions originating from the ³P₀ and ¹D₂ energy levels to the ³H_(J=6, 5, 4) and ³F_(J=2, 3, 4) energy levels all localized in the 4f² intra-configuration of the Pr³⁺ ions with a dominant emission at 614 nm corresponding to the ³P₀ \rightarrow ³H₆ transition. It was also noticed that there was no emission from ZnO nanoparticles (usually at ~370 and 560 nm), instead the red emission of Pr³⁺ was enhanced when ZnO nanoparticles. That is, energy was transferred non-radiatively from ZnO to Pr³⁺. The transfer was most probably by phonon mediated processes as previously reported [8-10].



Fig.3 CL spectra SiO₂, SiO₂:0.2 mol% Pr^{3+} and ZnO.SiO₂:0.2 mol% Pr^{3+} irradiated with 2 keV, 20 μ A beam of electrons in a high vacuum chamber containing 1.6 x 10⁻⁸ Torr.

Figure 4 presents the PL emission spectra of SiO₂:0.2 mol% Pr^{3+} and ZnO.SiO₂:0.2 mol% Pr^{3+} phosphors under excitation at 90 nm using synchrotron radiation. Also, only characteristic emissions from Pr^{3+} ion with the main red emission centred at 614 nm were detected from both SiO₂: Pr^{3+} and ZnO.SiO₂: Pr^{3+} phosphors. The PL intensity of ZnO.SiO₂: Pr^{3+} was enhanced with ZnO incorporation indicating energy transfer from ZnO to Pr^{3+} ions.



Fig. 4 PL emission spectra of SiO₂:0.2 mol% Pr^{3+} and ZnO.SiO₂:0.2 mol% Pr^{3+} after VUV excitation at 90 nm using synchrotron radiation. The inset shows the PL emission spectrum of ZnO nanoparticles after excitation at 325 nm.

Note that the emission spectrum from ZnO could not be measured due to charging when exciting using synchrotron radiation. However the spectra was recorded when a monochromatized xenon lamp (λ_{exc} = 325 nm) was used as shown in the inset in figure 4. The direct band gap emission and green emission from the ZnO nanoparticles was measured at 365 nm and 517 nm, respectively. Based on these results it was then concluded that the energy transfer from ZnO could be due to bandgap absorption and relaxation to the defects states of ZnO [9].

3.3. CL properties of SiO₂: $Ce^{3+}-Pr^{3+}$.

Figure 5 shows the CL emission spectra of SiO₂:1 mol% Ce³⁺ phosphor powder under irradiation with 2 keV electrons, 8.5 μ A beam current in a high vacuum chamber at a base pressure of 1.2 x 10⁻⁸ Torr. The CL emission spectrum from SiO₂:Ce³⁺ consists of two blue bands located at 452 nm (shoulder) and 494 nm (strong). The two bands at 452 nm and 494 nm can be associated with ²D_{3/2}-²F_{7/2} and ²D_{3/2}-²F_{5/2} of Ce³⁺, respectively [7].



Fig. 5 CL emission spectra of SiO₂:Ce³⁺ (1mol %) irradiated with 2 keV, 8.5 μ A beam of electrons in a high vacuum chamber containing a base pressure of 1.2 x10⁻⁸ Torr.

The CL emission spectra of the SiO₂:Pr³⁺, SiO₂:Ce³⁺, and SiO₂:Pr³⁺.Ce³⁺ (with different Ce³⁺ concentrations) phosphor powders under irradiation with 2 keV electrons, 8.5 μ A beam current in a high vacuum chamber at a base pressure of 1.2 x 10⁻⁸ Torr are shown in figure 6. The CL emission spectra of SiO₂:Ce³⁺-Pr³⁺ showed both bands from Ce³⁺ in the blue spectral region and a small shoulder from Pr³⁺ in the red spectral region when the amount of Pr³⁺ and Ce³⁺ were both 0.2 mol%. The small shoulder from Pr³⁺ was slowly quenched with increasing Ce³⁺ concentration and only blue emission from Ce³⁺ into 0.2 mol% Pr³⁺ compared to singly doped SiO₂:Ce³⁺. These results suggest the energy transfer from Pr³⁺ ions to its nearest neighbouring Ce³⁺ ions. In addition, it appears that at 1 mol% of Ce³⁺, the Ce³⁺ neighbouring ions are close enough to each other for energy transfer from Pr³⁺ to Ce³⁺ to take place. An increase in Ce³⁺ concentration led to the shortening of the distance between its neighbouring ions as a result of non-radiative loss of excitation energy between Ce³⁺ ions favoring quenching effect thus decreasing luminescence intensity. The quenching of the CL intensity of SiO₂:Pr³⁺.Ce³⁺ with increasing Ce³⁺ concentration is demonstrated in the inset of figure 6.



Fig. 6 CL emission spectra of the SiO₂:Pr³⁺ (1mol %), SiO₂:Ce³⁺ (1mol %), and SiO₂:Pr³⁺ (0.2mol %) - Ce³⁺ (0.2, 1, 1.5, 2mol %) irradiated with 2 keV, 8.5 μ A beam of electrons in a high vacuum chamber containing a base pressure of 1.2 x10⁻⁸ Torr. The insert shows the CL intensity as a function of different Ce³⁺ concentrations.

4. Conclusion

Enhanced red and blue emissions from Pr^{3+} and Ce^{3+} due to energy transfer from ZnO and Pr^{3+} respectively were demonstrated. The luminescence enhancement of Pr^{3+} due to energy transfer from ZnO to Pr^{3+} in ZnO.SiO₂: Pr^{3+} was confirmed by both PL and CL analysis. Addition of 1 mol% Ce^{3+} to 0.2 mol% Pr^{3+} led to quenching of Pr^{3+} emission while the blue emission from Ce^{3+} was slightly enhanced as compared to SiO₂: Ce^{3+} indicating an energy transfer from Pr^{3+} to Ce^{3+} . The excitation energy was most probably transferred by phonon mediated processes.

5. Acknowledgements

This work was financially supported by the Department of Science and Technology of South Africa and the Council for Scientific and Industrial Research of South Africa.

6. References

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